



PRODUCT BULLETIN # 20496

Generic Copy

Issue Date: 05-Jun-2014

TITLE: Device Test Transfer of Space Image Sensors HAS2 and STAR1000

PROPOSED FIRST SHIP DATE: 05-Jun-2014

AFFECTED CHANGE CATEGORY(S): Device Test Location

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor sales office or <Gretel.Willems@onsemi.com>

DESCRIPTION AND PURPOSE:

ON Semiconductor wishes to announce that Device Test location of the affected part numbers has changed from ON Semiconductor Mechelen to ON Semiconductor Oudenaarde.

Released Site:

- ON Semiconductor Oudenaarde, Belgium

This transfer is intended to increase the overall capacity and improve the customer delivery performance.

List of affected General Parts:

NOIH2SM1000A-HHC
NOIH2SM1000S-HHC
NOIH2SM1000T-HHC
NOIS1SM1000A-HHC
NOIS1SM1000S-HHC

List of affected Customer Specific Parts:

NOIH2SM1000A-HWC
NOIH2SM1000S-HWC
NOIS1SM1000A-HWC
NOIS1SM1000S-HWC